L Number	Hits	Search Text	DB	Time stamp
39	1	JP-11339242-$.did.	JPO; DERWENT	2004/09/28 13:37
40	1	2000-211652.NRAN.	DERWENT	2004/09/28 13:37
38	2	JP-2001034938-$.did.	JPO; DERWENT	2004/09/28 13:38
41	31	((((((optical magnet$4 compact master) near3 disc) (MRM MD CD master) (record$3 near3 medium)) and (etch$4 ablat$4 abrad$4 form$4 remov$4 polish$4)) and (groove track trench)) and (magnetic adj film)) and (mask resist photoresist etch?stop))	EPO; JPO; DERWENT; IBM_TDB	2004/09/28 14:37
42	1412	((((((optical magnet$4 compact master) near3 disc) (MRM MD CD master) (record$3 near3 medium)) and (etch$4 ablat$4 abrad$4 form$4 remov$4 polish$4)) and (groove track trench)) and (magnetic adj film)) and (mask resist photoresist etch?stop))	USPAT; US-PGPUB	2004/09/28 14:38
43	16641	master near5 (disc information medium recording)	USPAT; US-PGPUB	2004/09/28 14:39
44	1153	(master near5 (disc information medium recording)) same magnetic	USPAT; US-PGPUB	2004/09/28 14:39
45	332	((master near5 (disc information medium recording)) same magnetic) same (groove trench track)	USPAT; US-PGPUB	2004/09/28 14:39
46	8	(((master near5 (disc information medium recording)) same magnetic) same (groove trench track)) same (silicon "Si")	USPAT; US-PGPUB	2004/09/28 14:39
47	10	(((master near5 (disc information medium recording)) same magnetic) same (groove trench track)) same (silicon "Si" semiconductor)	USPAT; US-PGPUB	2004/09/28 14:39
48	0	6613459.URPN.	USPAT	2004/09/28 14:44
49	7	("4363844" | "5637373" | "5677051" | "5703733" | "5768075" | "6347016" | "6433944").PN.	USPAT	2004/09/28 14:44
68	1643	(silicon adj dioxide silicon adj oxide "sio.sub.2") with (mask resist) with (silicon "Si") with (groove trench via track) with (etch$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 15:06
69	598	((silicon adj dioxide silicon adj oxide "sio.sub.2") with (mask resist) with (silicon "Si") with (groove trench via track) with (etch$4)) same (thickness depth micron micrometer ".mu.")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 15:06
70	29	(((silicon adj dioxide silicon adj oxide "sio.sub.2") with (mask resist) with (silicon "Si") with (groove trench via track) with (etch$4)) same (thickness depth micron micrometer ".mu.")) and (disc disk)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 15:06
131	5	("4125427" | "4180432" | "4259433" | "4350561" | "4512848").PN.	USPAT	2004/09/28 15:31
132	18	4724043.URPN.	USPAT	2004/09/28 15:32
154	13	("3383760" | "3859178" | "4417946" | "4437226" | "4561932" | "4670092" | "4776924" | "4814287" | "4845048" | "5072288" | "5112771" | "5156988" | "5198390").PN.	USPAT	2004/09/28 15:41
155	59	5198390.URPN.	USPAT	2004/09/28 15:50
179	20	5770465.URPN.	USPAT	2004/09/28 16:05

180	63	(US-6788641-$ or US-6623652-$ or US-6419845-$ or US-6264848-$ or US-5700540-$ or US-6402973-$ or US-5770465-$ or US-6773782-$ or US-6706358-$ or US-5580639-$ or US-4057831-$ or US-5998261-$ or US-6284606-$ or US-5915192-$ or US-6530141-$ or US-6515475-$ or US-5713122-$ or US-4608293-$ or US-4299680-$ or US-6613459-$ or US-6583957-$ or US-6242162-$ or US-4797316-$ or US-4724043-$ or US-5652687-$ or US-4772929-$).did. or (US-6020270-$ or US-6770388-$ or US-5724339-$ or US-5199023-$ or US-6709976-$ or US-6153443-$ or US-5242539-$ or US-4983253-$ or US-4452507-$ or US-5393375-$ or US-6090712-$ or US-5215623-$ or US-5148257-$ or US-5576918-$ or US-6703099-$ or US-6670032-$).did. or (US-20030136973-$ or US-20020112343-$ or US-20020041463-$ or US-20040076110-$ or US-20010031549-$ or US-20020055018-$).did. or (EP-176684-$).did. or (JP-63119038-$ or JP-04310642-$ or JP-01235044-$ or JP-03263635-$ or JP-63071957-$ or JP-03137821-$ or JP-04325943-$ or JP-03209641-$).did. or (JP-05189743-$ or JP-04251435-$ or JP-07296328-$ or JP-2001034938-$ or JP-11339242-$).did. or (NB8406505).tban.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 16:26
183	11	((US-6788641-$ or US-6623652-$ or US-6419845-$ or US-6264848-$ or US-5700540-$ or US-6402973-$ or US-5770465-$ or US-6773782-$ or US-6706358-$ or US-5580639-$ or US-4057831-$ or US-5998261-$ or US-6284606-$ or US-5915192-$ or US-6530141-$ or US-6515475-$ or US-5713122-$ or US-4608293-$ or US-4299680-$ or US-6613459-$ or US-6583957-$ or US-6242162-$ or US-4797316-$ or US-4724043-$ or US-5652687-$ or US-4772929-$).did. or (US-6020270-$ or US-6770388-$ or US-5724339-$ or US-5199023-$ or US-6709976-$ or US-6153443-$ or US-5242539-$ or US-4983253-$ or US-4452507-$ or US-5393375-$ or US-6090712-$ or US-5215623-$ or US-5148257-$ or US-5576918-$ or US-6703099-$ or US-6670032-$).did. or (US-20030136973-$ or US-20020112343-$ or US-20020041463-$ or US-20040076110-$ or US-20010031549-$ or US-20020055018-$).did. or (EP-176684-$).did. or (JP-63119038-$ or JP-04310642-$ or JP-01235044-$ or JP-03263635-$ or JP-63071957-$ or JP-03137821-$ or JP-04325943-$ or JP-03209641-$).did. or (JP-05189743-$ or JP-04251435-$ or JP-07296328-$ or JP-2001034938-$ or JP-11339242-$).did. or (NB8406505).tban.) and soft	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 16:27

| | 298 | ("4279623" "4291353" "6183891" "5784226" "4325093" "5531016" "4272795" "4290088" "4291346" "4296448" "4626781" "5313356" "5483735" "5828527" "5875079" "4476152" "4608293" "4855854" "5323282" "5576085" "5617276" "5689225" "6081113" "4525808" "4546391" "4562502" "4564877" "4576876" "4578775" "4604669" "4612587" "4756960" "4809111" "4812935" "4839761" "4858048" "4933792" "4939609" "5327313" "5475550" "5577020" "5637028" "5671105" "5726964" "5825594" "5837392" "5843565" "5858548" "5956267" "6064551").pn. ("6120920" "6172857" "6204995" "4516222" "4618901" "4792711" "4840842" "5027247" "5202862" "5277960" "5314745" "5325344" "5335453" | USPAT | 2004/09/22 12:15 |

PLUS

SEARCH

"5409058"
"5495378"

-	571	(216/22).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 12:15
-	351	((216/22).CCLS.) and (disc record$3 adj medium)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 12:59
-	308	(216/39).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 14:43
-	223	(216/72).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 15:03
-	1641	(369/275.1).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 15:03
-	1936	(369/275.4).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 15:03
-	3301	(369/283).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 15:04
-	1266	(369/288).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 15:04
-	1396	(((369/275.1).CCLS.) ((369/275.4).CCLS.) ((369/283).CCLS.) ((369/288).CCLS.)) and (silicon "si" "sio.sub.2")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:53
-	204	((((369/275.1).CCLS.) ((369/275.4).CCLS.) ((369/283).CCLS.) ((369/288).CCLS.)) and (silicon "si" "sio.sub.2")) and etch$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 15:05
-	518	(((369/275.1).CCLS.) ((369/275.4).CCLS.) ((369/283).CCLS.) ((369/288).CCLS.)) and etch$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 15:35
-	314	((((369/275.1).CCLS.) ((369/275.4).CCLS.) ((369/283).CCLS.) ((369/288).CCLS.)) and etch$4) not (((((369/275.1).CCLS.) ((369/275.4).CCLS.) ((369/283).CCLS.) ((369/288).CCLS.)) and (silicon "si" "sio.sub.2")) and etch$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 15:59

-	1118	(216/79).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 16:00
-	102	(216/74).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 16:01
-	81	((216/79).CCLS.) and (disc record$3 adj medium)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 16:33
-	5	5993679.URPN.	USPAT	2004/09/22 16:10
-	141118	(disc record$3 adj medium) with (magnet$5 master)	USPAT; US-PGPUB	2004/09/22 17:08
-	437	((disc record$3 adj medium) with (magnet$5 master)) same (groove? trench) same (etch$4 remov$4 ablat$4 abrad$4 polish$4)	USPAT; US-PGPUB	2004/09/22 16:35
-	25	(((disc record$3 adj medium) with (magnet$5 master)) same (groove? trench) same (etch$4 remov$4 ablat$4 abrad$4 polish$4)) same (silicon silica$4 "si" "sio.sub.2")	USPAT; US-PGPUB	2004/09/22 16:38
-	412	(((disc record$3 adj medium) with (magnet$5 master)) same (groove? trench) same (etch$4 remov$4 ablat$4 abrad$4 polish$4)) not ((((disc record$3 adj medium) with (magnet$5 master)) same (groove? trench) same (etch$4 remov$4 ablat$4 abrad$4 polish$4)) same (silicon silica$4 "si" "sio.sub.2"))	USPAT; US-PGPUB	2004/09/22 16:38
-	12	("3894179" | "4307178" | "4724043" | "5147763" | "5149607" | "5286583" | "5471455" | "5645978" | "5799007" | "5898553" | "5917799" | "6071586").PN.	USPAT	2004/09/22 16:49
-	0	6242162.URPN.	USPAT	2004/09/22 16:50
-	456832	((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)	USPAT; US-PGPUB	2004/09/22 17:47
-	58618	(((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) same (etch$4 remov$4 ablat$4 abrad$4 polish$4)	USPAT; US-PGPUB	2004/09/22 17:10
-	34651	(((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) with (etch$4 remov$4 ablat$4 abrad$4 polish$4)	USPAT; US-PGPUB	2004/09/22 17:10
-	176	((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) with (etch$4 remov$4 ablat$4 abrad$4 polish$4)) same (silicon silica$4 "si") same (silicon adj dioxide silicon adj oxide "sio.sub.2")	USPAT; US-PGPUB	2004/09/22 17:12
-	172	(((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) with (etch$4 remov$4 ablat$4 abrad$4 polish$4)) same (silicon silica$4 "si") same (silicon adj dioxide silicon adj oxide "sio.sub.2")) not (((disc record$3 adj medium) with (magnet$5 master)) same (groove? trench) same (etch$4 remov$4 ablat$4 abrad$4 polish$4))	USPAT; US-PGPUB	2004/09/22 17:32

-	1936	((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) with (etch$4 remov$4 ablat$4 abrad$4 polish$4)) same (groove trench track)	USPAT; US-PGPUB	2004/09/22 17:33
-	25	(((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) with (etch$4 remov$4 ablat$4 abrad$4 polish$4)) same (groove trench track)) same (magnetic adj film)	USPAT; US-PGPUB	2004/09/22 17:40
-	5	("4935278" | "5768075" | "6055139" | "6180208" | "6268978").PN.	USPAT	2004/09/22 17:35
-	60	(((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) with (etch$4 remov$4 ablat$4 abrad$4 polish$4)) same (groove trench track)) same (silicon "si" "sio.sub.2")	USPAT; US-PGPUB	2004/09/22 17:41
-	59	((((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) with (etch$4 remov$4 ablat$4 abrad$4 polish$4)) same (groove trench track)) same (silicon "si" "sio.sub.2")) not ((((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) with (etch$4 remov$4 ablat$4 abrad$4 polish$4)) same (groove trench track)) same (magnetic adj film))	USPAT; US-PGPUB	2004/09/22 17:41
-	960928	((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)	EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:47
-	382067	(((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) and (etch$4 ablat$4 abrad$4 form$4 remov$4 polish$4)	EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:48
-	27907	((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) and (etch$4 ablat$4 abrad$4 form$4 remov$4 polish$4)) and (groove track trench)	EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:48
-	6701	(((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) and (etch$4 ablat$4 abrad$4 form$4 remov$4 polish$4)) and (groove track trench)) and (silicon "si" "sio.sub.2" silica)	EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:49
-	0	((((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) and (etch$4 ablat$4 abrad$4 form$4 remov$4 polish$4)) and (groove track trench)) and (silicon "si" "sio.sub.2" silica)) and (fill deposit smooth) and (magnetic adj film)	EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:49
-	36	((((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) and (etch$4 ablat$4 abrad$4 form$4 remov$4 polish$4)) and (groove track trench)) and (silicon "si" "sio.sub.2" silica)) and (magnetic adj film)	EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:52
-	545	(((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) and (etch$4 ablat$4 abrad$4 form$4 remov$4 polish$4)) and (groove track trench)) and (magnetic adj film)	EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:52
-	31	((((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) and (etch$4 ablat$4 abrad$4 form$4 remov$4 polish$4)) and (groove track trench)) and (magnetic adj film)) and (mask resist photoresist etch?stop)	EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:53

-	29	((((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) and (etch$4 ablat$4 abrad$4 form$4 remov$4 polish$4)) and (groove track trench)) and (magnetic adj film)) and (mask resist photoresist etch?stop)) not ((((((optical magnet$4 compact master) near3 disc) (MRM MD CD) (record$3 near3 medium)) and (etch$4 ablat$4 abrad$4 form$4 remov$4 polish$4)) and (groove track trench)) and (silicon "si" "sio.sub.2" silica)) and (magnetic adj film))	EPO; JPO; DERWENT; IBM_TDB	2004/09/28 13:53
-	2602	(etch$4) with (silicon) same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask resist etch?stop)) same (groove track trench)	USPAT; US-PGPUB	2004/09/22 18:50
-	19	(disc record$3 adj medium).ti,ab,clm. and ((etch$4) with (silicon) same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask resist etch?stop)) same (groove track trench))	USPAT; US-PGPUB	2004/09/23 11:26
-	14	(etch$4) and (silicon) and ((silicon adj oxide silicon adj dioxide "sio.sub.2") and (mask resist etch?stop)) and (groove track trench) and (disc record$3 adj medium)	EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:41
-	2	JP-07296328-$.did.	JPO; DERWENT	2004/09/23 13:11
-	1	1996-024856.NRAN.	DERWENT	2004/09/22 18:45
-	1	((etch$4) with (silicon) same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask resist etch?stop)) same (groove track trench)) same (deposit fill apply) same (magnetic)	USPAT; US-PGPUB	2004/09/22 18:51
-	12	((etch$4) with (silicon) same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask resist etch?stop)) same (groove track trench)) same (magnetic)	USPAT; US-PGPUB	2004/09/22 18:51
-	267	(((369/275.1).CCLS.) ((369/275.4).CCLS.) ((369/283).CCLS.) ((369/288).CCLS.)) and ("magnetic film")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:54
-	230	((((369/275.1).CCLS.) ((369/275.4).CCLS.) ((369/283).CCLS.) ((369/288).CCLS.)) and ("magnetic film")) not ((((369/275.1).CCLS.) ((369/275.4).CCLS.) ((369/283).CCLS.) ((369/288).CCLS.)) and etch$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:54
-	67	(disc record$3 adj medium magnetic).ti,ab,clm. and ((etch$4) with (silicon) same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask resist etch?stop)) same (groove track trench))	USPAT; US-PGPUB	2004/09/23 12:03
-	2612	((etch$4) with (silicon) same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask resist etch?stop)) same (groove track trench))	USPAT; US-PGPUB	2004/09/23 15:11
-	1629	(((etch$4) with (silicon) same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask resist etch?stop)) same (groove track trench))) same (coat apply deposit film sputter cover fill)	USPAT; US-PGPUB	2004/09/23 13:06
-	10	(((etch$4) with (silicon) same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask resist etch?stop)) same (groove track trench))) same ((coat apply deposit film sputter cover fill) with (magnet$4 ferromagnet$4))	USPAT; US-PGPUB	2004/09/23 12:20
-	341	(((etch$4) with (silicon) same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask resist etch?stop)) same (groove track trench))) same ((coat cover fill))	USPAT; US-PGPUB	2004/09/23 14:48

-	3	(((etch$4) with (silicon) same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask resist etch?stop)) same (groove track trench))) same (disc)	USPAT; US-PGPUB	2004/09/23 13:06
-	1	1996-024856.NRAN.	DERWENT	2004/09/23 13:07
-	1	("5652687").PN.	USPAT	2004/09/23 13:11
-	14	("3614339" | "4550353" | "4551911" | "4675986" | "4689877" | "4839197" | "4843507" | "4878290" | "5111352" | "5282308" | "5283942" | "5285340" | "5289325" | "5452164").PN.	USPAT	2004/09/23 13:11
-	61	5652687.URPN.	USPAT	2004/09/23 13:12
-	0	176684.URPN.	USPAT	2004/09/23 13:46
-	0	176684.URPN.	USPAT	2004/09/23 13:46
-	7	("5047274" | "5277960" | "5356513" | "5576918" | "5820769" | "5923511" | "6055139").PN.	USPAT	2004/09/23 13:54
-	25	5576918.URPN.	USPAT	2004/09/23 13:56
-	6	6264848.URPN.	USPAT	2004/09/23 13:58
-	28	("4546398" | "4735840" | "4974110" | "RE33949" | "5241520" | "5399372" | "5518804" | "5543221" | "5589262" | "5615205" | "5635267" | "5703733" | "5889641" | "5942342" | "5986978" | "5999512" | "6042927" | "6248416" | "6261681" | "6264848" | "6270885" | "6277484" | "6387483" | "6403240" | "6411459" | "6421313" | "6462916" | "6531202" | "2001/0045005").PN.	USPAT	2004/09/23 14:01
-	0	6703099.URPN.	USPAT	2004/09/23 14:06
-	1	JP-04176021-$.did.	JPO; DERWENT	2004/09/23 14:08
-	1	JP-03263635-$.did.	JPO; DERWENT	2004/09/23 14:25
-	450	yoshimura-hiroyuki.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 15:12
-	33	yoshimura-hiroyuki.in. and disc	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 15:20
-	74549	"fuji electric".as.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 15:21
-	2306	"fuji electric".as. and disc	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 15:21
-	384	("fuji electric".as. and disc) and (groove trench track)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 15:24

-	9	(("fuji electric".as. and disc) and (groove trench track)) and etch$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 15:22
-	4	(("fuji electric".as. and disc) and (groove trench track)) and fill	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 16:11
-	2618	(fill cover) with (groove track trench) same (etch)	USPAT; US-PGPUB	2004/09/23 16:27
-	12	((fill cover) with (groove track trench) same (etch)) same magnetic	USPAT; US-PGPUB	2004/09/23 16:13
-	15	("4417393" | "4803338" | "4871630" | "5595941" | "5658826" | "5710066" | "5719089" | "5802700" | "5863707" | "5867890" | "5907775" | "5910871" | "6100014" | "6136696" | "6140201" | "2003/0128460").PN.	USPAT	2004/09/23 16:15
-	817	(fill cover) with (groove track trench) same ((etch) with (silicon silica$4 "si" "sio.sub.2"))	USPAT; US-PGPUB	2004/09/23 16:28
-	63	((fill cover) with (groove track trench) same ((etch) with (silicon silica$4 "si" "sio.sub.2"))) same ((silicon adj dioxide silicon adj oxide) with (mask resist etch?stop hard?mask))	USPAT; US-PGPUB	2004/09/23 16:46
-	571	(428/694ML).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 17:22
-	232	((428/694ML).CCLS.) and (groove trench track)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 16:48
-	1	"5407755".PN.	USPAT	2004/09/23 17:03
-	1	5700540.URPN.	USPAT	2004/09/23 17:03
-	1268	(428/694T).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 17:41
-	271	((428/694T).CCLS.) and (groove track trench)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 17:23
-	265	(((428/694T).CCLS.) and (groove track trench)) not (((428/694ML).CCLS.) and (groove trench track))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 17:23
-	2	("4565734" | "4889767").PN.	USPAT	2004/09/23 17:29
-	0	5571595.URPN.	USPAT	2004/09/23 17:29
-	319	(428/694BR).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 17:50

-		97	((428/694BR).CCLS.) and (groove track trench)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 17:46
-		494	(428/694ST).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 17:51
-		126	((428/694ST).CCLS.) and (groove track trench)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 17:51
-		644	(428/694SG).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 17:51
-		209	((428/694SG).CCLS.) and (groove track trench)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 17:51
-		8	("3099571" | "4391849" | "4472240" | "4875987" | "4911967" | "4935278" | "5336586" | "5350618").PN.	USPAT	2004/09/23 18:02
-		4	5580639.URPN.	USPAT	2004/09/23 18:03
-		12	("3894179" | "4307178" | "4724043" | "5147763" | "5149607" | "5286583" | "5471455" | "5645978" | "5799007" | "5898553" | "5917799" | "6071586").PN.	USPAT	2004/09/24 16:33
-		447	(trifluoromethane "chf.sub.3") with (oxygen "o.sub.2") with (silicon adj dioxide silicon adj oxide "sio.sub.2")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 16:52
-		415	((trifluoromethane "chf.sub.3") with (oxygen "o.sub.2") with (silicon adj dioxide silicon adj oxide "sio.sub.2")) with etch$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 16:52
-		46	(((trifluoromethane "chf.sub.3") with (oxygen "o.sub.2") with (silicon adj dioxide silicon adj oxide "sio.sub.2")) with etch$4) with (trench groove via track)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 16:59
-		198	(sulfur adj fluoride sulfur adj hexafluoride "sf.sub.6") with (silicon "Si") with (groove trench via track) with (etch$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:38
-		29	(silicon adj dioxide silicon adj oxide "sio.sub.2") with (mask resist) same ((sulfur adj fluoride sulfur adj hexafluoride "sf.sub.6") with (silicon "Si") with (groove trench via track) with (etch$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 15:05

-	16043	(width depth dimension) with (trench groove track) same (disc magnetic adj record)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:29
-	42	((width depth dimension) with (trench groove track) same (disc magnetic adj record)) same (silicon "si") same (silicon adj oxide silicon adj dioxide "sio.sub.2")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:11
-	904	(width depth dimension) with (trench groove track) with narrow same (disc magnetic adj record)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:40
-	5	((width depth dimension) with (trench groove track) with narrow same (disc magnetic adj record)) same (silicon "si")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:29
-	370	((width depth dimension) with (trench groove track) with narrow same (disc magnetic adj record)) same (data information)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:32
-	0	(((width depth dimension) with (trench groove track) with narrow same (disc magnetic adj record)) same (silicon "si")) same (micron micrometer "mum")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:33
-	26	(((width depth dimension) with (trench groove track) with narrow same (disc magnetic adj record)) same (data information)) same (micron micrometer "mum")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:33
-	6904	(depth deep shallow) with (trench groove track) same (disc magnetic adj record)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:41
-	407	((depth deep shallow) with (trench groove track) same (disc magnetic adj record)) same (micron "mum" micrometer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:41
-	46	(((depth deep shallow) with (trench groove track) same (disc magnetic adj record)) same (micron "mum" micrometer)) same magnetic	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:51
-	7	(disc magnetic adj record$4) same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask etch?stop resist) with (etch$4) with (thick thickness micron ".mu." micrometre nanometer))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:55
-	9	(disc magnetic adj record$4) same etch$4 same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask etch?stop resist) with (thick thin thickness micron ".mu." micrometre nanometer))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:57

-		2	((disc magnetic adj record$4) same etch$4 same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask etch?stop resist) with (thick thin thickness micron ".mu." micrometre nanometer))) not ((disc magnetic adj record$4) same ((silicon adj oxide silicon adj dioxide "sio.sub.2") with (mask etch?stop resist) with (etch$4) with (thick thickness micron ".mu." micrometre nanometer)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/24 17:57
-		7	("4363844" | "5637373" | "5677051" | "5703733" | "5768075" | "6347016" | "6433944").PN.	USPAT	2004/09/27 12:37
-		220	(sulfur adj fluoride sulfur adj hexafluoride "sf.sub.6") with (silicon "Si") with (groove trench via track) with (etch$4) with (vapor gas RIE plasma)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:39
-		58	(US-5713122-$ or US-4608293-$ or US-4299680-$ or US-6788641-$ or US-6623652-$ or US-6419845-$ or US-6264848-$ or US-6402973-$ or US-5770465-$ or US-6706358-$ or US-5580639-$ or US-4057831-$ or US-5700540-$ or US-6613459-$ or US-6583957-$ or US-6242162-$ or US-4797316-$ or US-4724043-$ or US-5652687-$ or US-4772929-$ or US-6020270-$ or US-6770388-$ or US-5724339-$ or US-5199023-$ or US-6709976-$ or US-6153443-$).did. or (US-4983253-$ or US-5242539-$ or US-4452507-$ or US-5393375-$ or US-6090712-$ or US-5215623-$ or US-5148257-$ or US-5576918-$ or US-6703099-$ or US-6670032-$ or US-5998261-$ or US-6284606-$ or US-5915192-$ or US-6530141-$ or US-6515475-$).did. or (US-20020041463-$ or US-20040076110-$ or US-20010031549-$ or US-20030136973-$ or US-20020112343-$).did. or (EP-176684-$).did. or (JP-63119038-$ or JP-03263635-$ or JP-63071957-$ or JP-04310642-$ or JP-01235044-$ or JP-04325943-$ or JP-03209641-$).did. or (JP-07296328-$ or JP-05189743-$ or JP-04251435-$).did. or (NB8406505).tban.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:45

| - | | 29 | ((US-5713122-$ or US-4608293-$ or US-4299680-$ or US-6788641-$ or US-6623652-$ or US-6419845-$ or US-6264848-$ or US-6402973-$ or US-5770465-$ or US-6706358-$ or US-5580639-$ or US-4057831-$ or US-5700540-$ or US-6613459-$ or US-6583957-$ or US-6242162-$ or US-4797316-$ or US-4724043-$ or US-5652687-$ or US-4772929-$ or US-6020270-$ or US-6770388-$ or US-5724339-$ or US-5199023-$ or US-6709976-$ or US-6153443-$).did. or (US-4983253-$ or US-5242539-$ or US-4452507-$ or US-5393375-$ or US-6090712-$ or US-5215623-$ or US-5148257-$ or US-5576918-$ or US-6703099-$ or US-6670032-$ or US-5998261-$ or US-6284606-$ or US-5915192-$ or US-6530141-$ or US-6515475-$).did. or (US-20020041463-$ or US-20040076110-$ or US-20010031549-$ or US-20030136973-$ or US-20020112343-$).did. or (EP-176684-$).did. or (JP-63119038-$ or JP-03263635-$ or JP-63071957-$ or JP-04310642-$ or JP-01235044-$ or JP-04325943-$ or JP-03209641-$).did. or (JP-07296328-$ or JP-05189743-$ or JP-04251435-$).did. or (NB8406505).tban.) and ((groove track trench) with (depth height)) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/09/27 14:31 |

		29	((US-5713122-$ or US-4608293-$ or US-4299680-$ or US-6788641-$ or US-6623652-$ or US-6419845-$ or US-6264848-$ or US-6402973-$ or US-5770465-$ or US-6706358-$ or US-5580639-$ or US-4057831-$ or US-5700540-$ or US-6613459-$ or US-6583957-$ or US-6242162-$ or US-4797316-$ or US-4724043-$ or US-5652687-$ or US-4772929-$ or US-6020270-$ or US-6770388-$ or US-5724339-$ or US-5199023-$ or US-6709976-$ or US-6153443-$).did. or (US-4983253-$ or US-5242539-$ or US-4452507-$ or US-5393375-$ or US-6090712-$ or US-5215623-$ or US-5148257-$ or US-5576918-$ or US-6703099-$ or US-6670032-$ or US-5998261-$ or US-6284606-$ or US-5915192-$ or US-6530141-$ or US-6515475-$).did. or (US-20020041463-$ or US-20040076110-$ or US-20010031549-$ or US-20030136973-$ or US-20020112343-$).did. or (EP-176684-$).did. or (JP-63119038-$ or JP-03263635-$ or JP-63071957-$ or JP-04310642-$ or JP-01235044-$ or JP-04325943-$ or JP-03209641-$).did. or (JP-07296328-$ or JP-05189743-$ or JP-04251435-$).did. or (NB8406505).tban.) not (((US-5713122-$ or US-4608293-$ or US-4299680-$ or US-6788641-$ or US-6623652-$ or US-6419845-$ or US-6264848-$ or US-6402973-$ or US-5770465-$ or US-6706358-$ or US-5580639-$ or US-4057831-$ or US-5700540-$ or US-6613459-$ or US-6583957-$ or US-6242162-$ or US-4797316-$ or US-4724043-$ or US-5652687-$ or US-4772929-$ or US-6020270-$ or US-6770388-$ or US-5724339-$ or US-5199023-$ or US-6709976-$ or US-6153443-$).did. or (US-4983253-$ or US-5242539-$ or US-4452507-$ or US-5393375-$ or US-6090712-$ or US-5215623-$ or US-5148257-$ or US-5576918-$ or US-6703099-$ or US-6670032-$ or US-5998261-$ or US-6284606-$ or US-5915192-$ or US-6530141-$ or US-6515475-$).did. or (US-20020041463-$ or US-20040076110-$ or US-20010031549-$ or US-20030136973-$ or US-20020112343-$).did. or (EP-176684-$).did. or (JP-63119038-$ or JP-03263635-$ or JP-63071957-$ or JP-04310642-$ or JP-01235044-$ or JP-04325943-$ or JP-03209641-$).did. or (JP-07296328-$ or JP-05189743-$ or JP-04251435-$).did. or (NB8406505).tban.) and ((groove track trench) with (depth height)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:54
-		1	1993-275581.NRAN.	DERWENT	2004/09/27 14:10
-		9495	(disc magnetic adj recording magnetic adj medium).ti,ab,clm. and (track groove trench) with (dimension width)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:40
-		722	((disc magnetic adj recording magnetic adj medium).ti,ab,clm. and (track groove trench) with (dimension width)) and (micron ".mu." micrometer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:33

-	237	(((disc magnetic adj recording magnetic adj medium).ti,ab,clm. and (track groove trench) with (dimension width)) and (micron ".mu." micrometer)) and (magnetic adj film magnetic adj layer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:33
-	43	(((disc magnetic adj recording magnetic adj medium).ti,ab,clm. and (track groove trench) with (dimension width)) and (micron ".mu." micrometer)) and (magnetic adj film magnetic adj layer) with (depth height dimension)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:34
-	5417	(optical adj disc magnetic adj recording magnetic adj medium).ti,ab,clm. and (track groove trench) with (dimension width)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 16:46
-	266	((optical adj disc magnetic adj recording magnetic adj medium).ti,ab,clm. and (track groove trench) with (dimension width)) and (magnetic adj layer magnetic adj film) with (depth height dimension)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:41
-	230	(((optical adj disc magnetic adj recording magnetic adj medium).ti,ab,clm. and (track groove trench) with (dimension width)) and (magnetic adj layer magnetic adj film) with (depth height dimension)) not ((((disc magnetic adj recording magnetic adj medium).ti,ab,clm. and (track groove trench) with (dimension width)) and (micron ".mu." micrometer)) and (magnetic adj film magnetic adj layer) with (depth height dimension))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 15:55
-	2	WO-9803972-$.did. JP-1040544-$.did. JP-1125455-$.did.	EPO; JPO; DERWENT	2004/09/27 15:56
-	5	WO-9803972-$.did. JP-10040544-$.did. JP-11025455-$.did.	EPO; JPO; DERWENT	2004/09/27 15:56
-	8	("3099571" | "4391849" | "4472240" | "4875987" | "4911967" | "4935278" | "5336586" | "5350618").PN.	USPAT	2004/09/27 16:22
-	4	5580639.URPN.	USPAT	2004/09/27 16:24
-	96	((optical adj disc magnetic adj recording magnetic adj medium).ti,ab,clm. and (track groove trench) with (dimension width)) and (fill deposit cover) with (magnetic adj film magnetic adj layer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 16:47
-	5	("4125427" | "4180432" | "4259433" | "4350561" | "4512848").PN.	USPAT	2004/09/27 17:05
-	18	4724043.URPN.	USPAT	2004/09/27 17:06
-	1	1992-345755.NRAN.	DERWENT	2004/09/27 17:53
-	0	EP-0120990-$.did.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 18:20
-	0	EP-0120990-$.did.	EPO	2004/09/27 18:21
-	0	0120990-$.did.	EPO	2004/09/27 18:21
-	0	"0120990"	EPO	2004/09/27 18:21
-	36	"0120990"	EPO; DERWENT	2004/09/27 18:24

-	2	JP-61100910-$.did.	EPO; JPO; DERWENT	2004/09/27 18:26
-	2	JP-61054857-$.did.	EPO; JPO; DERWENT	2004/09/27 18:27
-	0	EP-0120990-$.did.	EPO; JPO; DERWENT	2004/09/27 18:27
-	2	EP-120990-$.did.	EPO; JPO; DERWENT	2004/09/27 18:28
-	1	WO-8809979-$.did.	EPO; JPO; DERWENT	2004/09/27 18:28